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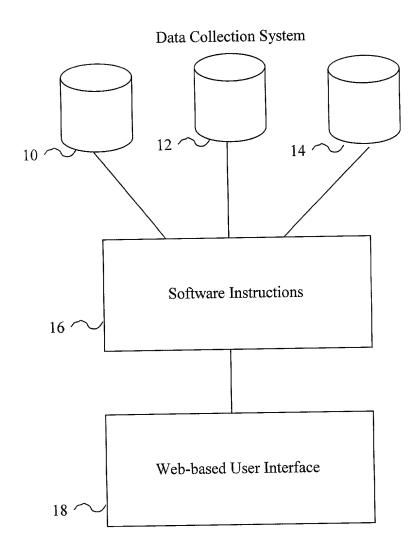


FIG.1

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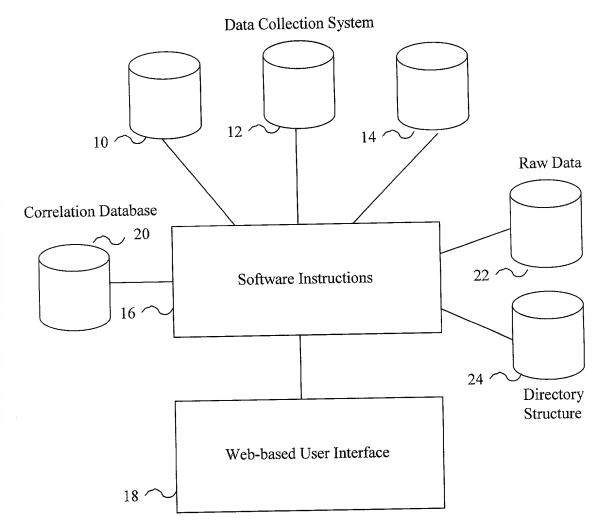


FIG.2

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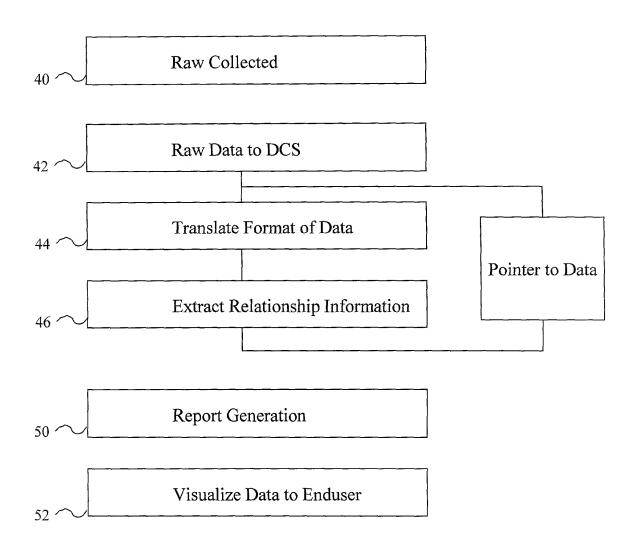
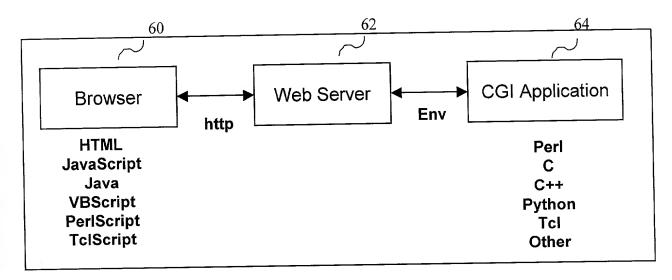


FIG.3

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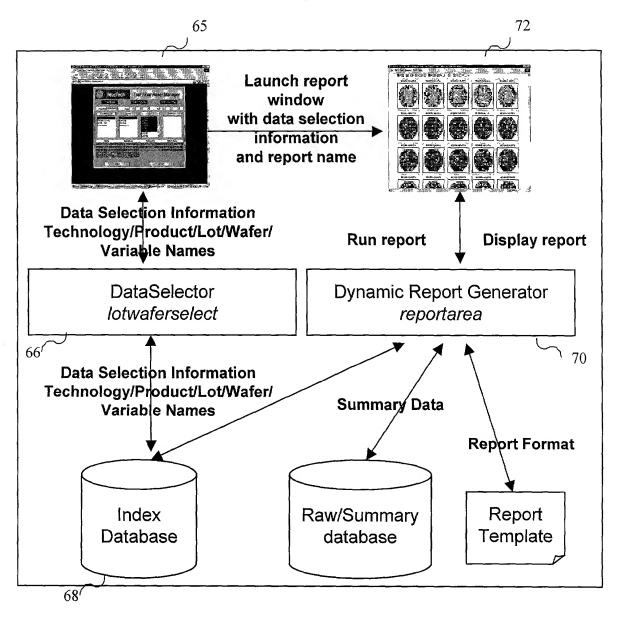


FIG.5

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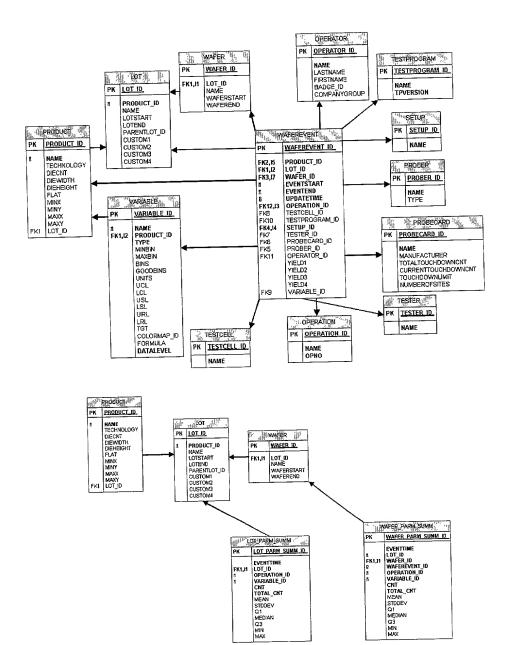


FIG.6

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Report Name	Report Description	Example
Lot Summary	A tabular reports that displays the lot bin summary for the selected lots. Click on an individual lot name to drill down to a Wafer Summary report	1
Lot Bin Histogram	Bar chart of bin count totals for selected lots.	The state of the s
Lot Yield Trend	Line trend chart of lot yields of the selected lots.	The first of 1990 1990 1990 1990 1990 1990 1990 199
Lot Yield Box Plot	Displays the distribution of wafer yields for the selected lots in a single report. The wafer yields are represented as a standard box plot.	The second secon
Bin Summary	A tabular report that displays the wafer bin summary for the selected wafers. Click on an individual wafer name to drill down to a Bin Map report.	Absorber 193 To have a second and a second a
		€ ** • • • • • • • • • • • • • • • • • •

FIG.7 (Sheet 1)

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Report Name	Report Description	Example
Wafer Bin Histogram	Bar chart of bin count totals for selected wafers.	The first control of the control of
Yield by Probe Card	Line trend chart of wafer yields of all selected wafers, sorted by probe card.	Proposed in the same dependent of the same
Yield by Operator	Line trend chart of wafer yields of all selected wafers, sorted by operator.	Constitution and the constitution of the const
Wafer Test Times	A bar chart that plots the actual time taken to test a wafer and the associated yield trend line for that wafer.	No Image Available
Lot Test Times	A bar chart that plots the actual time taken to test a lot, and the associated yield trend line for that lot.	The state of the s

FIG.7 (Sheet 2)

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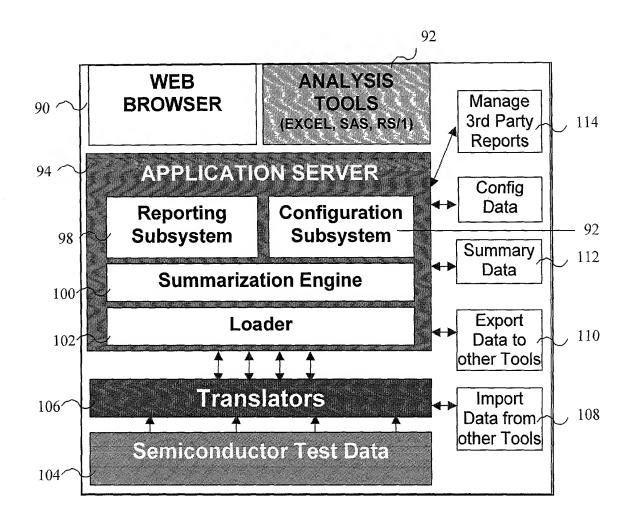
Report Name	Report Description	Example
Yield by Tester	Line trend chart of wafer yields of all selected wafers, sorted by tester.	No Image Available
86		
Yield by Prober	Line trend chart of wafer yields of all selected wafers, sorted by prober.	The state of the s
		#ministrational and and it is believed to the control of the contr
Parameter Gallery	Display a table of maps where each column is a parameter and each row is a wafer. Displays wafer maps for all parameters declared for the selected device. Click on an individual wafer map to zoom into that map. Use the browser "Back" button to return to the gallery.	The second secon
Wafer Yield Trend	Line trend chart of wafer yields of the selected wafers.	The second of th
Bin Map	Displays a bin map of the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected. FIG.7 (Sheet 3)	The state of the

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Report Name	Report Description	Example
Pass/Fail Bin Map	Displays a pass/fail map for the selected wafers. This report uses the device configuration information to determine the pass bins. Displays maps for all wafers in the selected lots if no individual wafers are selected.	The state of the s
Bin Gallery	Displays a pass/fail map for the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected. Click on an individual wafer map to zoom into that map.	The second secon
Percent Composite	Displays a composite yield map for the selected wafers. This report uses the device configuration information to determine the pass bins.	Special control of the second

FIG.7 (Sheet 4)

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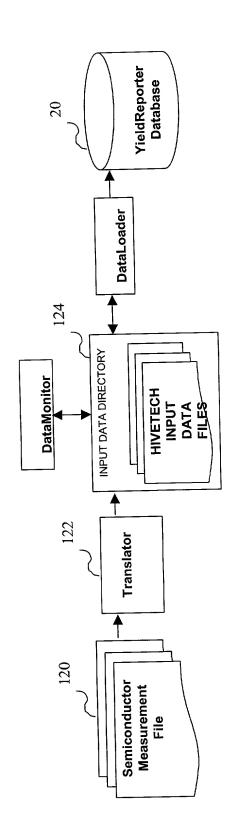
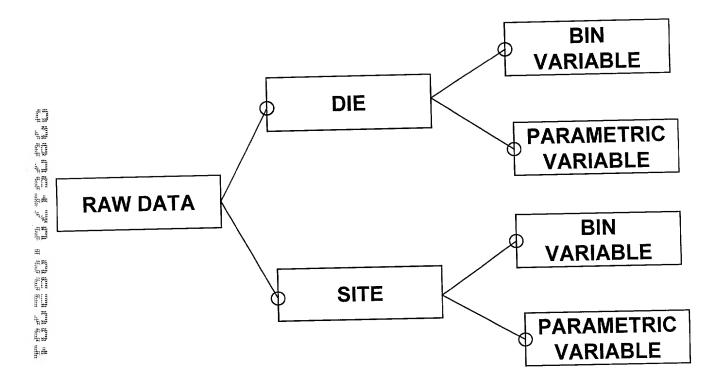
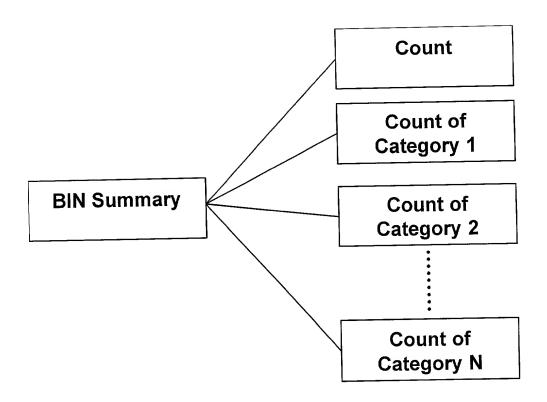


FIG.9



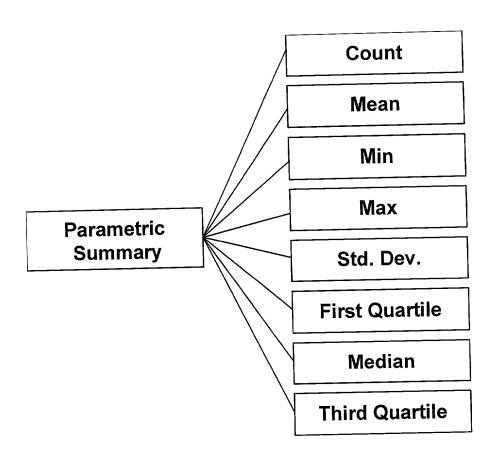
Variable Types

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Lot or Wafer Bin Summary

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Lot or Wafer Parametric Summary